Power MOSFET

30 V, 58 A, Single N-Channel, DPAK/IPAK

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- AEC-Q101 Qualified and PPAP Capable NVD4809NH
- These Devices are Pb-Free and are RoHS Compliant

Applications

- CPU Power Delivery
- DC-DC Converters
- Low Side Switching

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Param	Symbol	Value	Unit		
Drain-to-Source Voltag	V _{DSS}	30	V		
Gate-to-Source Voltage	е		V_{GS}	±20	V
Continuous Drain		T _A = 25°C	I _D	11.5	Α
Current (R _{θJA}) (Note 1)		T _A = 85°C		9.0	
Power Dissipation (R _{θJA}) (Note 1)		T _A = 25°C	P _D	2.0	W
Continuous Drain		T _A = 25°C	I _D	9.0	Α
Current ($R_{\theta JA}$) (Note 2)	Steady	T _A = 85°C		7.0	
Power Dissipation $(R_{\theta JA})$ (Note 2)	State	T _A = 25°C	P _D	1.3	W
Continuous Drain		T _C = 25°C	I _D	58	Α
Current (R _{θJC}) (Note 1)	-	T _C = 85°C		45	
Power Dissipation (R _{θJC}) (Note 1)		T _C = 25°C	P _D	52	W
Pulsed Drain Current	t _p =10μs	T _A = 25°C	I _{DM}	130	Α
Current Limited by Pack	age	T _A = 25°C	I _{DmaxPkg}	45	Α
Operating Junction and	T _J , T _{stg}	-55 to 175	°C		
Source Current (Body Di	I _S	43	Α		
Drain to Source dV/dt	dV/dt	6.0	V/ns		
Single Pulse Drain-to-S Energy (V_{DD} = 24 V, V_{GS} L = 1.0 mH, $I_{L(pk)}$ = 15 A	E _{AS}	112.5	mJ		
Lead Temperature for So (1/8" from case for 10 s)	Idering Pu	rposes	T _L	260	°C

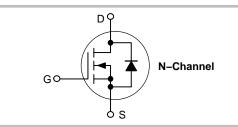
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



ON Semiconductor®

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V _{(BR)DSS} R _{DS(on)} MAX		I _D MAX
30 V	9.0 mΩ @ 10 V	58 A
30 V	12.5 mΩ @ 4.5 V	30 A



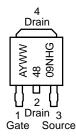


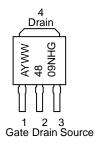
DPAK CASE 369AA (Bent Lead) STYLE 2



IPAK
CASE 369AD
(Straight Lead)
STYLE 2

MARKING DIAGRAMS & PIN ASSIGNMENTS





A = Assembly Location*
Y = Year
WW = Work Week

4809NH= Device Code
G = Pb-Free Package

* The Assembly Location code (A) is front side optional. In cases where the Assembly Location is stamped in the package, the front side assembly code may be blank.

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 6 of this data sheet.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	2.9	°C/W
Junction-to-TAB (Drain)	$R_{\theta JC-TAB}$	3.5	
Junction-to-Ambient - Steady State (Note 1)	$R_{ heta JA}$	74	
Junction-to-Ambient - Steady State (Note 2)	$R_{ heta JA}$	116	

- 1. Surface-mounted on FR4 board using 1 in sq pad size, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS (T₁ = 25°C unless otherwise noted)

Parameter	Symbol	Test Co	ndition	Min	Тур	Max	Unit
OFF CHARACTERISTICS			•		•	1	
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				25		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}		$T_{J} = 25^{\circ}C$ $T_{J} = 125^{\circ}C$			1.0 10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V				±100	nA
ON CHARACTERISTICS (Note 3)	<u> </u>						
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}$, I	_D = 250 μA	1.5	2.1	2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.7		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}		I _D = 30 A		7.0	9.0	mΩ
	11.5 V	I _D = 15 A		7.0			
	V _{GS} :	V _{GS} = 4.5 V	I _D = 30 A		10.45	12.5	
			I _D = 15 A		9.95		
Forward Transconductance	g _{FS}	V _{DS} = 15 V	I _D = 15 A		9.0		S
CHARGES AND CAPACITANCES							
Input Capacitance	C _{iss}				1596	2155	pF
Output Capacitance	C _{oss}	$V_{GS} = 0 \text{ V, f}$ $V_{DS} =$	= 1.0 MHz, 12 V		331	447	1
Reverse Transfer Capacitance	C _{rss}	50			190	294	
Total Gate Charge	Q _{G(TOT)}				12.5	15	nC
Threshold Gate Charge	Q _{G(TH)}	$V_{GS} = 4.5 V,$	V _{DS} = 15 V,		2.4	3.6	
Gate-to-Source Charge	Q_{GS}	$I_D = 3$	80 Å		5.3	7.9	
Gate-to-Drain Charge	Q_{GD}				5.1	7.7	
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = 11.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_D = 30 \text{ A}$			29.3	44	nC
SWITCHING CHARACTERISTICS (Note 4)							
Turn-On Delay Time	t _{d(on)}				12.0	18	ns
Rise Time	t _r	$V_{GS} = 4.5 V,$	V _{DS} = 15 V,		20	30	
Turn-Off Delay Time	t _{d(off)}	$I_D = 15 \text{ A, F}$	$R_G = 3.0 \Omega$		14	21	
Fall Time	t _f				5.0	7.5	1

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

- 3. Pulse Test: Pulse Width ≤ 300 µs, Duty Cycle ≤ 2%.
- 4. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted) (continued)

Parameter	Symbol	Test Co	ndition	Min	Тур	Max	Unit
Turn-On Delay Time	t _{d(on)}				7.0	10.4	ns
Rise Time	t _r	V _{GS} = 11.5 V,	V _{DS} = 15 V,		18	27	
Turn-Off Delay Time	t _{d(off)}	I _D = 15 A, F	$R_G = 3.0 \Omega$		22	33	
Fall Time	t _f	1			3.0	4.6	
DRAIN-SOURCE DIODE CHARACTERIS	rics						
Forward Diode Voltage	V_{SD}	V _{GS} = 0 V,	$V_{GS} = 0 \text{ V}, \qquad T_{J} = 25^{\circ}\text{C}$		0.95	1.2	V
		$I_S = 30 \text{ A}$ $T_J = 125^{\circ}\text{C}$		0.83			
Reverse Recovery Time	t _{RR}				15.6		ns
Charge Time	ta	$V_{GS} = 0 \text{ V, dls/}$	dt = 100 A/μs,		10.6		
Discharge Time	tb	$I_S = 3$	30 A		5.0		
Reverse Recovery Time	Q _{RR}	1			7.5		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L _S				2.49		nΗ
Drain Inductance, DPAK	L _D	1			0.0164		
Drain Inductance, IPAK	L _D	T _A = 25°C			1.88		
Gate Inductance	L _G				3.46		
Gate Resistance	R _G	1			0.75		Ω

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

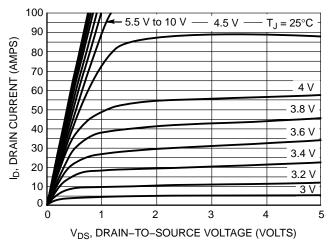
3. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2%.

^{4.} Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES

80

 $V_{DS} \ge 10 \text{ V}$

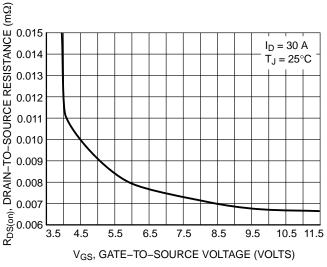


70 **DRAIN CURRENT (AMPS)** 60 50 40 30 $T_J = 125^{\circ}C$ 20 $T_J = 25^{\circ}C$ ئے 10 $T_J = -55^{\circ}C$ 0 2 3 5 1

Figure 1. On-Region Characteristics

V_{GS}, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 2. Transfer Characteristics



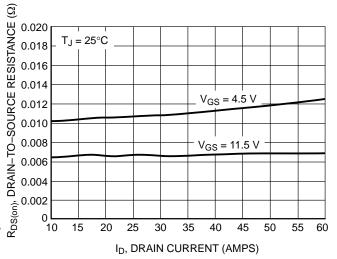
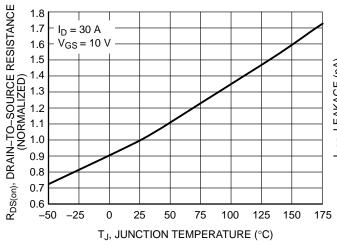


Figure 3. On–Resistance vs. Gate–to–Source Voltage

Figure 4. On–Resistance vs. Drain Current and Gate Voltage



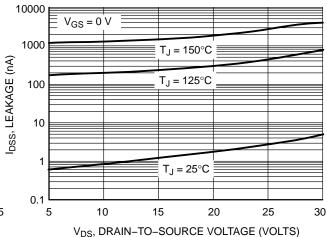


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Drain Voltage

TYPICAL PERFORMANCE CURVES

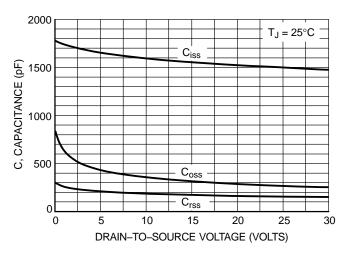


Figure 7. Capacitance Variation

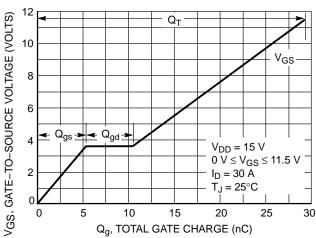


Figure 8. Gate-to-Source Voltage vs. Total Charge

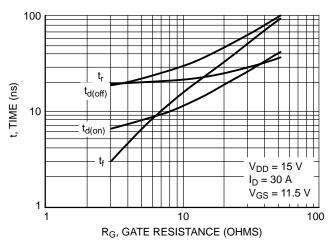


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

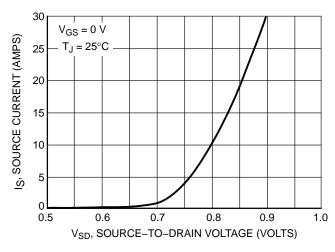


Figure 10. Diode Forward Voltage vs. Current

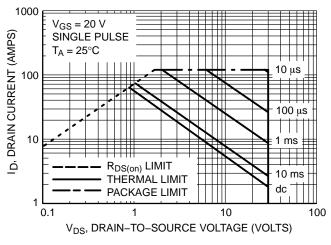


Figure 11. Maximum Rated Forward Biased Safe Operating Area

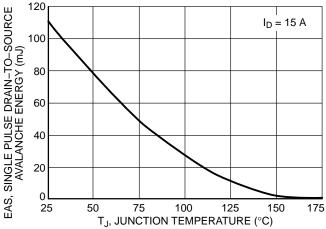


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL PERFORMANCE CURVES

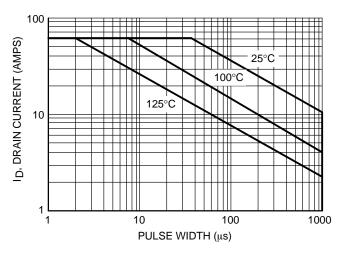


Figure 13. Avalanche Characteristics

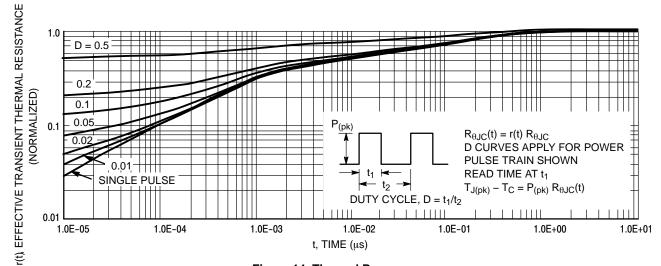


Figure 14. Thermal Response

ORDERING INFORMATION

Device	Package	Shipping [†]
NTD4809NHT4G	DPAK (Pb-Free)	2500 / Tape & Reel
NTD4809NH-35G	IPAK Trimmed Lead (3.5 \pm 0.15 mm) (Pb–Free)	75 Units / Rail
NVD4809NHT4G	DPAK (Pb-Free)	2500 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

STYLE 1: PIN 1. BASE

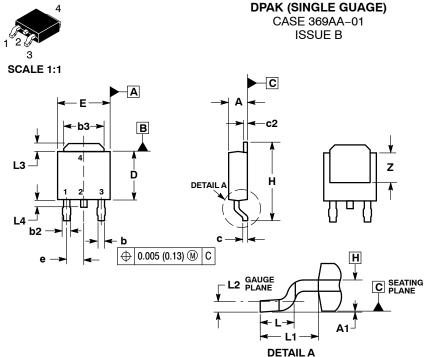
STYLE 5:

2. COLLECTOR 3. EMITTER

4. COLLECTOR

PIN 1. GATE 2. ANODE 3. CATHODE

4. ANODE



STYLE 3: PIN 1. ANODE

STYLE 7:

2. CATHODE 3. ANODE

PIN 1. GATE 2. COLLECTOR

3. EMITTER

COLLECTOR

CATHODE



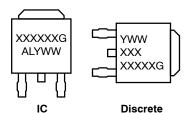
DATE 03 JUN 2010

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: INCHES.
 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z.
 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD
- FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INC	HES	MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
b	0.025	0.035	0.63	0.89
b2	0.030	0.045	0.76	1.14
b3	0.180	0.215	4.57	5.46
С	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
E	0.250	0.265	6.35	6.73
е	0.090	BSC	2.29 BSC	
Н	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.108	0.108 REF		REF
L2	0.020	0.020 BSC		BSC
L3	0.035	0.050	0.89	1.27
L4		0.040		1.01
Z	0.155		3.93	

GENERIC MARKING DIAGRAM*



XXXXXX = Device Code Α = Assembly Location L = Wafer Lot ٧ = Year = Work Week WW = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking.

SOLDERING FOOTPRINT*

STYLE 2: PIN 1. GATE

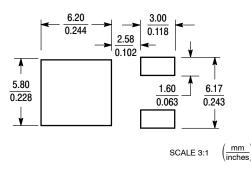
STYLE 6:

PIN 1. MT1 2. MT2

3. GATE

2. DRAIN 3. SOURCE

4. DRAIN



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

DOCUMENT NUMBER:	98AON13126D	Electronic versions are uncontrolled except when accessed directly from the Document Repositor Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	DPAK (SINGLE GAUGE)		PAGE 1 OF 1	

ROTATED 90° CW

STYLE 4: PIN 1. CATHODE 2. ANODE 3. GATE

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MECHANICAL CASE OUTLINE

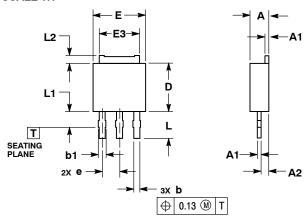


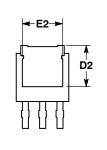
3.5 MM IPAK, STRAIGHT LEAD

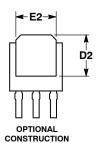
CASE 369AD **ISSUE B**

DATE 18 APR 2013









- NOTES:
 1.. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2.. CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION b APPLIES TO PLATED TERMINAL
- AND IS MEASURED BETWEEN 0.15 AND 0.30mm FROM TERMINAL TIP.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD GATE OR MOLD FLASH.

	MILLIMETERS				
DIM	MIN	MAX			
Α	2.19	2.38			
A1	0.46	0.60			
A2	0.87	1.10			
b	0.69	0.89			
b1	0.77	1.10			
D	5.97	6.22			
D2	4.80				
E	6.35	6.73			
E2	4.57	5.45			
E3	4.45	5.46			
е	2.28	BSC			
L	3.40	3.60			
L1		2.10			
L2	0.89	1.27			

GENERIC MARKING DIAGRAMS*

Integrated

STYLE '	1:
PIN 1.	BA

STYLE 5:

PIN 1. GATE

ASE 2. COLLECTOR 3. **EMITTER**

ANODE
 CATHODE

ANODE

COLLECTOR

STYLE 2: PIN 1. GATE

STYLE 6:

PIN 1. MT1

MT2
 GATE

MT2

2. DRAIN 3. SOURCE DRAIN

STYLE 3: PIN 1. ANODE 2. CATHODE

3. ANODE CATHODE

STYLE 7:

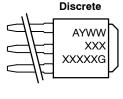
PIN 1. GATE 2. COLLECTOR 3. EMITTER

COLLECTOR

STYLE 4: PIN 1. CATHODE

2. ANODE 3. GATE

ANODE





XXXXXX = Device Code

Α = Assembly Location

L = Wafer Lot Υ = Year WW = Work Week G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

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DESCRIPTION:	3.5 MM IPAK, STRAIGHT L	EAD	PAGE 1 OF 1	

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